

<b>Notice of References Cited</b>	Application/Control No. 10/808,537	Applicant(s)/Patent Under Reexamination ODA ET AL.	
	Examiner Yuk C. Chow	Art Unit 2609	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,028,745 A	07-1991	Yamanami et al.	178/18.07
*	B	US-5,434,372 A	07-1995	Lin, Chyi-Cheng	178/18.07
*	C	US-5,567,920 A	10-1996	Watanabe et al.	178/18.07
*	D	US-5,635,684 A	06-1997	Fukuzaki, Yasuhiro	178/18.07
*	E	US-5,675,130 A	10-1997	Sekizawa, Yasushi	178/18.07
*	F	US-5,682,019 A	10-1997	Katsurahira et al.	178/18.07
*	G	US-5,691,513 A	11-1997	Yamamoto et al.	178/18.07
*	H	US-6,020,849 A	02-2000	Fukuzaki, Yasuhiro	342/374
*	I	US-6,670,561 B2	12-2003	Aoki, Toshio	178/18.01
*	J	US-6,888,538 B2	05-2005	Ely et al.	345/173
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.